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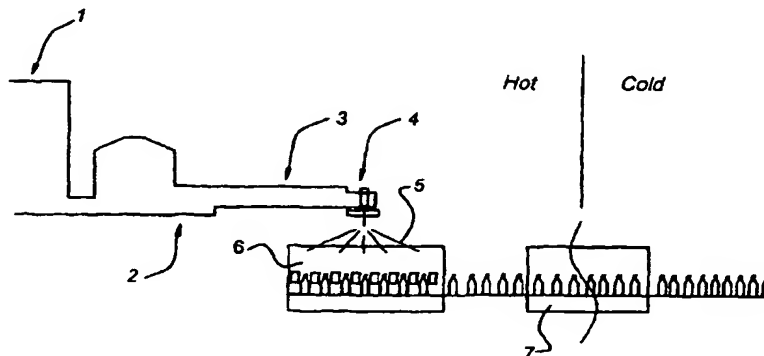
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(54) Title: ANALYTICAL SYSTEM AND METHOD FOR MEASURING AND CONTROLLING A PRODUCTION PROCESS



(57) Abstract: An analytical system for analysing and controlling a shaping process for glass products is described. The analytical system comprises an infrared-sensitive measurement system and a processor communicating therewith, the infrared-sensitive measurement system being equipped to measure infrared radiation originating from hot glass products immediately after the shaping process for the glass products and the processor being equipped to determine a heat distribution in the glass products on the basis of information determined by the measurement system. Because the infrared-sensitive measurement system is sensitive only to radiation in the so-called Near Infra Red (NIR) region, radiation originating from the interior of the glass wall can be measured. This makes novel analytical methods possible with which, inter alia, a distinction can be made between a change in glass wall thickness and a change in temperature.

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